11-10-03

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Docket: **BUR920020113US1**

Filing Date:	07/02/03	Examiner: Unassigned
Application No.:	10/604230	Group Art Unit: Unassigned
Applicant:	**Conti et al.**	Confirmation No.: Unknown

Title: **APPLYING PARAMETRIC TEST PATTERNS FOR HIGH PIN COUNT ASICs ON LOW PIN COUNT TESTERS.**

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT UNDER 37 CFR 1.56, 1.97, 1.98

Honorable Commissioner of Patents and Trademarks
Washington, D. C. 20231

Sir:

Applicants submit herewith form PTO-1449, listing patents, publications, or other information of which they are aware which they believe may be material to patentability pursuant to 37 CFR 1.56(b), and in respect of which there may be a duty to disclose under 37 CFR 1.56(a), together with legible copies of the patents, publications, or other information listed.

While the items submitted with this Information Disclosure Statement may be material to patentability pursuant to 37 CFR 1.56, in accordance with 37 CFR 1.97(h) it shall not be construed to be an admission that any patent, publication, or other information cited is "prior art" or is material to patentability for this invention unless specifically designated as such. In accordance with 37 CFR 1.97(g), the filing of this Information Disclosure Statement shall not be construed to mean that a search has been made or that no other information material to patentability, as defined in 37 CFR 1.56(b), exists.

This Information Disclosure Statement is being filed with the filing of this application. Accordingly, it is not believed that any fee is required relating to the filing of this Information Disclosure Statement. If this is not the case, the Patent Office is hereby authorized to charge any related fee to Deposit Account No. 09-0456.

Respectfully submitted,

Date: 11/06/03

By: Robert A. Walsh

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INFORMATION DISCLOSURE CITATION

(Use several sheets if necessary)

Docket Number (Optional)	Application Number
BUR920020113US1	10/604230
Applicant(s) Conti et al.	
Filing Date 07/02/03	**Group Art Unit**

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE

FOREIGN PATENT DOCUMENTS

	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation YES	Translation NO
		GB2342722A	2000/04/19	United Kingdon			✓	

OTHER DOCUMENTS *(Including Author, Title, Date, Pertinent Pages, Etc.)*

		'Special Test Chip For Testing IC Tester', IBM Technical Disclosure Bulletin, Vol. 28, No. 1, June 1985, pp. 221-222
		'N-Way Testpoint For Complex LSI Design', IBM Technical Disclosure Bulletinl, Vol. 13, No. 10, March 1972, pp. 2937-2938

EXAMINER	DATE CONSIDERED

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.